

Translation of PCT/EP2004/005728

New claims

- 5 1. High-frequency measuring system for measuring a
device under test (19), comprising a measuring-
device unit (2) and at least one high-frequency
module (3, 24, 25), wherein each high-frequency
10 module (3, 24, 25) can be placed spatially
separately from the measuring-device unit (2) and
each high-frequency module (3, 24, 25) can be
connected to the measuring-device unit (2) via a
digital interface (23, 26, 27),
characterised in that
15 the processing of input data to form a bitstream to
be transmitted via the digital interface (26) takes
place by assigning the symbols to states in the
state diagram of the I-Q (in phase - quadrature
phase) level in the measuring-device unit (2),
20 and/or that a digitised intermediate-frequency
signal is transmitted via the digital interface
(27).
- 25 2. High-frequency measuring system according to claim
1,
characterised in that
the high-frequency module (3, 24, 25) comprises a
transmitter device and/or a receiver device (28,
29) for communication with a device under test
30 (19).
3. High-frequency measuring system according to claim
1 or 2,
characterised in that

the digital interface (23, 26, 27) is a serial interface.

4. High-frequency measuring system according to claim
5 1 or 2,
characterised in that
the digital interface (23, 26, 27) is a parallel interface.
- 10 5. High-frequency measuring system according to any
one of claims 1 to 4,
characterised in that
the digital interface (23, 26, 27) is an optical
15 interface.
6. High-frequency measuring system according to any
one of claims 1 to 4,
characterised in that
the digital interface (23, 26, 27) is an electrical
20 interface.
7. High-frequency measuring system according to any
one of claims 1 to 6,
characterised in that
25 the at least one high-frequency module (3, 24, 25)
is supplied with electrical energy via a power-
supply unit (14, 40) independent from the
measuring-device unit (2).
- 30 8. High-frequency measuring system according to any
one of claims 1 to 7,
characterised in that

several identical ports (5.1, 5.2, 5.3) are provided on the measuring-device unit (2) for the digital interface (23).

- 5 9. High-frequency measuring system according to any
one of claims 1 to 8,
characterised in that
several different ports (5.1, 5.2, 5.3, 6.1, 6.2,
6.3) are provided on the measuring-device unit for
10 the digital interface (23).
10. High-frequency measuring system according to any
one of claims 1 to 9,
characterised in that
15 control data and/or user data can be transmitted in
a standardised form via the digital interface and
that the at least one high-frequency module (24')
comprises means for processing a high-frequency
signal with regard to the transmission of data in
20 standardised form via the digital interface and/or
for processing the data transmitted in standardised
form with regard to at least one given transmission
standard for the high-frequency signal.